Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/655,229	CHANG, CHUNG NAN
Examiner	Art Unit
Shin-Hon Chen	2131

SEARCHED					
Class	Subclass	Date	Examiner		
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	/	5.2.			
	<u>/</u>				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
USPAT, PGPUB, JPO, EPO, DERWENT (BRS search)	7/14/2006	S.C.
Inventor name search for double patenting issue	7/14/2006	S.C.